

U.S. Department of Commerce, Patent and Trademark Office		Atty Docket No.	Serial No. 10/067466
		M-12486 US	New application
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)		Applicant(s)	
		Calvet, et al.	
		Filing Date	Group 2874
		Herewith 2-4-02	Unknown

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 02/04/02

U.S. Patent Documents

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
JDL	AA	4,696,692	09/29/87	Schmitt	65	102	
JDL	AB	5,004,205	04/02/91	Brown et al.	248	476	
JDL	AC	5,163,108	11/10/92	Armiento et al.	385	89	
JDL	AD	5,469,893	11/28/95	Caveney et al.	138	162	
JDL	AE	5,678,944	10/21/97	Slocum et al.	403	13	
JDL	AF	5,733,024	03/31/98	Slocum et al.	312	223.2	
JDL	AG	5,748,827	05/05/98	Holl et al.	385	1.34	
JDL	AH	5,803,402	09/08/98	Krumweide et al.	244	117R	
JDL	AI	5,821,764	10/13/98	Slocum et al.	324	758	
JDL	AJ	5,857,049	01/05/99	Beranek et al.	385	91	
JDL	AK	5,905,831	05/18/99*	Boudreau et al.	385	88	

Foreign Patent Documents

Translation

		Document	Date	Country	Class	Subclass	Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AQ	
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Examiner John D. Lee Date Considered 04 NOV. 2003

*EXAMINER: Initial reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

U.S. Department of Commerce, Patent and Trademark Office		Atty Docket No.	Serial No. 10/061 468
		M-12487 US	New application
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U.S. Patent Documents							
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JDL	AA	5,913,002	06/15/99	Jiang	385	88	
JDL	AB	5,915,678	06/29/99	Slocum et al.	269	47	
JDL	AC	5,964,397	10/12/99	Dautartas	228	180.22	
JDL	AD	6,085,007	07/04/00	Jiang et al.	385	92	
JDL	AE	6,118,917	09/12/00	Lee et al.	285	49	
JDL	AF	6,127,254	10/03/00	Diebold et al.	438	613	
JDL	AG	6,157,759	12/05/00	Seo et al.	385	49	
JDL	AH	6,160,672	12/12/00	Chan et al.	359	819	
JDL	AI	6,170,157 B1	01/09/01	Munk et al.	29	897.2	
JDL	AJ	6,195,407 B1	02/27/01	Dobbs et al.	378	4	
JDL	AK	6,314,630 B1	11/13/01	Munk et al.	29	407.01	

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